# MSKSEMI















**ESD** 

TVS

TSS

MOV

**GDT** 

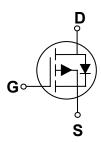
**PLED** 

# Brodnet data speet

www.msksemi.com



SOT-23-3L



#### **Features**

- $-20V, -3.3A, RDS(ON) = 30m\Omega@VGS = -4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

# **Applications**

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-20V	60mΩ	-3.3A

# **Absolute Maximum Ratings** Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V <sub>DS</sub>	Drain-Source Voltage	-20	V
Vgs	Gate-Source Voltage	±12	V
	Drain Current – Continuous (T <sub>C</sub> =250)	-3.3	А
lD	Drain Current – Continuous (T <sub>C</sub> =100C)	-2.5	А
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	-13.2	Α
D	Power Dissipation (T <sub>C</sub> =250)	1.56	W
P <sub>D</sub>	Power Dissipation – Derate above 250	0.012	W/ C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	С
TJ	Operating Junction Temperature Range	-55 to 150	С

#### **Thermal Ch aracteristics**

Symbol	Parameter	Тур.	Max.	Unit
Reja	Thermal Resistance Junction to ambient		80	C/ W

#### **Off Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250uA	-20			V
$\triangle BV_{DSS}/\triangle T_{J}$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 250 , I <sub>D</sub> =-1mA		-0.01		V/ C
Davis Outstand on Outstand		V <sub>DS</sub> =-20V , V <sub>GS</sub> =0V , T <sub>J</sub> =250			-1	uA
IDSS	Drain-Source Leakage Current	V <sub>DS</sub> =-16V , V <sub>GS</sub> =0V , T <sub>J</sub> =125C			-10	uA
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS=} \pm 12V$ , $V_{DS}=0V$			±10	uA

#### **On Characteristics**

R <sub>DS(ON)</sub>	RDS(ON) Static Drain-Source On-Resistance	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		60	90	mΩ	
T (DO(ON)	Static Brain-Source Sh-resistance	V <sub>GS</sub> =-2.5V , I <sub>D</sub> =-2A		90	120	11152	
$V_{GS(th)}$	Gate Threshold Voltage	\\ _\\   _ 050\	-0.4	-0.7	-1.2	V	
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$V_{GS}=V_{DS}$ , $I_D=-250uA$		3		mV/ C	
gfs	Forward Transconductance	V <sub>DS</sub> =-10V , I <sub>S</sub> =-1A		2.2		S	

**Dynamic and switching Characteristics** 

	and switching onaracteristi	•		
$Q_g$	Total Gate Charge <sup>2, 3</sup>		 4.8	
Q <sub>gs</sub>	Gate-Source Charge <sup>2, 3</sup>	$V_{DS}$ =-10V , $V_{GS}$ =-4.5V , $I_{D}$ =-3A	 0.5	 nC
$Q_{gd}$	Gate-Drain Charge <sup>2, 3</sup>		 1.9	
T <sub>d(on)</sub>	Turn-On Delay Time <sup>2,3</sup>		 3.5	
Tr	Rise Time <sup>2,3</sup>	$V_{DD}$ =-10V , $V_{GS}$ =-4.5V , $R_{G}$ =25 $\Omega$	 12.6	
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>2,3</sup>	I <sub>D</sub> =-1A	 32.6	 nS
T <sub>f</sub>	Fall Time <sup>2,3</sup>		 8.4	
Ciss	Input Capacitance		 550	
Coss	Output Capacitance	V <sub>DS</sub> =-10V , V <sub>GS</sub> =0V , F=1MHz	 65	 pF
C <sub>rss</sub>	Reverse Transfer Capacitance		 55	

### **Drain-Source Diode Characteristics and Maximum Ratings**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	\/ -\/ -0\/ Fares Current			-3.3	Α
lsм	Pulsed Source Current	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-6.6	Α
VsD	Diode Forward Voltage	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =250			-1.2	V

#### Note:

- Repetitive Rating : Pulsed width limited by maximum junction temperature.
  The data tested by pulsed, pulsed width < 200 methods and a contract of the contract of the
- The data tested by pulsed , pulse width  $\leq 300$ us , duty cycle  $\leq 2\%$ .
- 3. Essentially independent of operating temperature.

AO3419

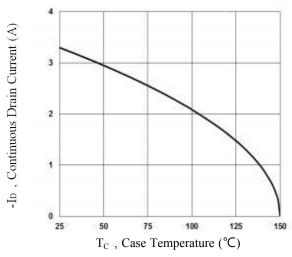


Fig.1 Continuous Drain Current vs. Tc

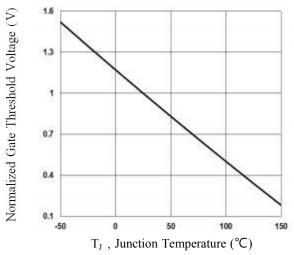
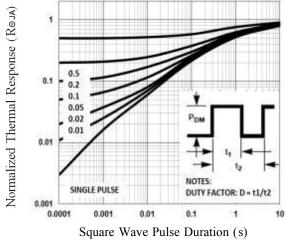
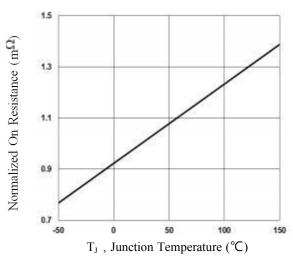


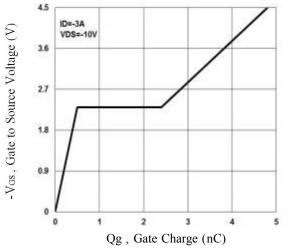
Fig.3 Normalized  $V_{th}$  vs.  $T_J$ 



**Normalized Transient Response** 



Normalized RDSON vs.  $T_J$ Fig.2



**Gate Charge Waveform** 

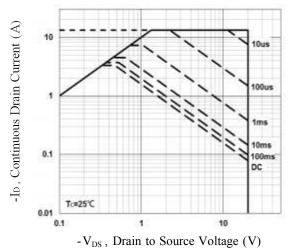
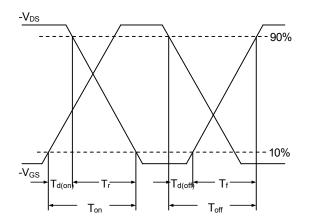


Fig.6 Maximum Safe Operation Area





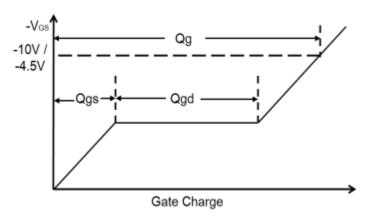
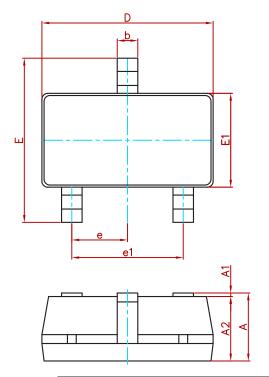
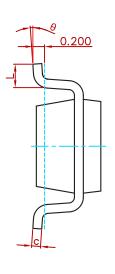


Fig. 7 Switching Time Waveform

Fig. 8 Gate Charge Waveform

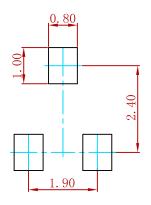
### **PACKAGE MECHANICAL DATA**





Symbol	Dimensions Ir	n Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950(	BSC)	0.037(	(BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
Α	٥°	8°	0°	8°

# **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.3.The pad layout is for reference purposes only.

# **REEL SPECIFICATION**

P/N	PKG	QTY
AO3419	SOT-23-3L	3000



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